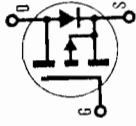


INTERNATIONAL RECTIFIER **IR**

**HEXFET® TRANSISTORS IRF9510**  
**IRF9511**  
**IRF9512**  
**IRF9513**



- Features:**
- P-Channel Versatility
  - Compact Plastic Package
  - Fast Switching
  - Low Drive Current
  - Ease of Paralleling
  - Excellent Temperature Stability

**-100 Volt, 1.2 Ohm HEXFET TO-220AB Plastic Package**

The HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry and unique structure of the HEXFET design achieve very low on-state resistance combined with high transconductance and extreme device ruggedness.

The P-Channel HEXFETs are designed for applications which require the convenience of reversal polarity operation. They retain all of the features of the more popular N-Channel HEXFETs such as voltage control, fast switching, ease of paralleling, and excellent temperature stability. The P-Channel IRF9510 device is an approximate electrical complement to the N-Channel IRF510 HEXFET.

P-Channel HEXFETs are intended for use in power stages where complementary symmetry with N-Channel devices offers circuit simplification. They are also very useful in drive stages because of the versatility offered by the reverse polarity connection. Applications include motor control, audio amplifiers, switched mode converters, control circuit and pulse amplifiers.

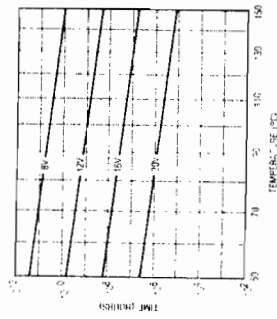


Fig. 18 — Typical Time to Accumulated 1% Gate Failure

The data shown is current as of April 15, 1987. This information is updated on a quarterly basis. For the latest reliability data, please contact your local IR rep. 2-198

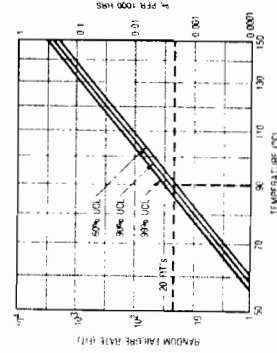


Fig. 19 — Typical High Temperature Reverse Bias (HTRB) Failure Rate

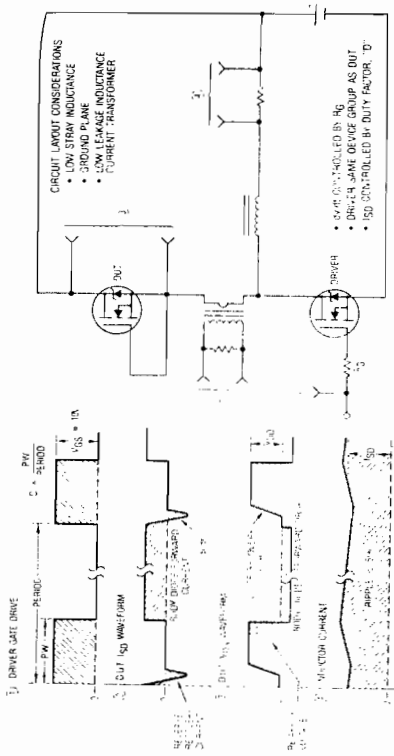
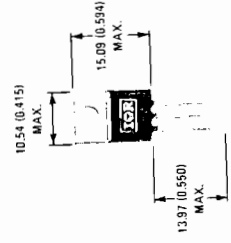


Fig. 17 — Peak Diode Recovery dv/dt Test Circuit

**CASE STYLE AND DIMENSIONS**



Case Style TO-220AB  
All Dimensions in Millimeters and (Inches)

Absolute Maximum Ratings

Parameter	IRF9510	IRF9511	IRF9512	IRF9513	Units
$V_{GS}$ Drain-Source Voltage ①	-100	-80	-100	-80	V
$V_{DS}$ Drain-Source Voltage ②	-100	-80	-100	-80	V
$I_D$ @ $T_C = 25^\circ\text{C}$ Continuous Drain Current	-3.0	-2.5	-3.0	-2.5	A
$I_D$ @ $T_C = 100^\circ\text{C}$ Continuous Drain Current	-3.0	-2.5	-3.0	-2.5	A
$I_{DM}$ Pulsed Drain Current ③	-12	-10	-12	-10	A
$V_{GS}$ Gate-Source Voltage	-12	-10	-12	-10	V
$P_D$ @ $T_C = 25^\circ\text{C}$ Max. Power Dissipation	2.0	(See Fig. 14)	2.0	(See Fig. 14)	W
Linear Derating Factor	0.16	(See Fig. 14)	0.16	(See Fig. 14)	W/K
$T_J$ Junction Temperature	-12	-10	-12	-10	°C
Storage Temperature Range	-55 to 150		-55 to 150		°C

Electrical Characteristics @  $T_C = 25^\circ\text{C}$  (Unless Otherwise Specified)

Parameter	Type	Min.	Typ.	Max.	Units	Test Conditions
$V_{DS(DD)}$ Drain-Source Breakdown Voltage	IRF9510 IRF9511 IRF9512 IRF9513	-100 -80 -100 -80			V	$V_G = 0V$ $I_D = -250\mu A$
$V_{GS(th)}$ Gate Threshold Voltage	ALL	-4.0			V	$V_{DS} = V_{GS}$ , $I_D = -250\mu A$
$V_{GS(on)}$ Gate-Source On Voltage	ALL	-4.0			V	$V_{DS} = V_{GS}$ , $I_D = -250\mu A$
$V_{DS(on)}$ Drain-Source On Voltage	ALL	-500			nA	$V_{GS} = 20V$
$V_{DS(0)}$ Zero Gate Voltage Drain Current	ALL	-250			$\mu A$	$V_{GS} = \text{Max. Rating}$ , $V_{DS} = 0V$
$I_{D(on)}$ On-State Drain Current ②	IRF9510 IRF9511 IRF9512 IRF9513	-3.0 -2.5 -3.0 -2.5			A	$V_{GS} = \text{Max. Rating}$ , $V_{DS} = 0V$ , $T_C = 125^\circ\text{C}$
$R_{DS(on)}$ Static Drain-Source On-State Resistance ②	IRF9510 IRF9511 IRF9512 IRF9513	1.0 1.0 1.0 1.0	1.2	1.6	$\Omega$	$V_{GS} = 10V$ , $I_D = -1.5A$
$R_{th}$ Forward Transconductance ②	ALL	0.8	1.1	1.5	$\text{S}$	$V_{GS} = 10V$ , $I_D = -1.5A$
$C_{iss}$ Input Capacitance	ALL	180	250		pF	$V_{GS} = 0V$ , $V_{DS} = 25V$ , $f = 1.0\text{ MHz}$
$C_{oss}$ Output Capacitance	ALL	85	100		pF	See Fig. 10
$t_{r(on)}$ Turn-On Delay Time	ALL	30	35		ns	See Fig. 17
$t_{f(on)}$ Turn-Off Delay Time	ALL	15	30		ns	See Fig. 17
$t_{f(off)}$ Fall Time	ALL	20	40		ns	See Fig. 17
$t_{g}$ Total Gate Charge (Gate-Source Plus Gate-Drain)	ALL	8.5	11		nC	$V_{GS} = 15V$ , $I_D = -4A$ , $V_{DS} = 0V$ , $V_{GS} = 0V$ , $V_{GS} = 15V$
$Q_{gs}$ Gate-Source Charge	ALL	3.8			nC	See Fig. 18 for test circuit. (Gate charge is essentially independent of operating temperature.)
$Q_{gd}$ Gate-Drain ("Miller") Charge	ALL	4.7			nC	See Fig. 18 for test circuit. (Gate charge is essentially independent of operating temperature.)
$L_D$ Internal Drain Inductance	ALL	3.5			nH	Measured from the package lead to the center of the die.
$L_S$ Internal Source Inductance	ALL	4.5			nH	Measured from the package lead to the center of the die.

Thermal Resistance

$R_{JA}$ Junction-to-Air	ALL	6.4	WK/°C
$R_{JC}$ Junction-to-Case	ALL	1.0	WK/°C
$R_{JA}$ Junction-to-Ambient	ALL	80	WK/°C

Source-Drain Diode Ratings and Characteristics

Parameter	IRF9510	IRF9511	IRF9512	IRF9513	Units
$I_S$ Continuous Source Current (Body Diode)	-3.0		-3.0		A
$I_{SM}$ Pulse Source Current (Body Diode) ③	-12		-12		A
$V_{SD}$ Diode Forward Voltage ④	-5.5		-5.5		V
$t_{rr}$ Reverse Recovery Time	-5.3		-5.3		ns
$t_{fwd}$ Forward Turn-On Time	ALL	120	ALL	120	ns
$t_{fwd}$ Forward Turn-Off Time	ALL	6.0	ALL	6.0	ns

①  $T_J = 25^\circ\text{C}$  to  $150^\circ\text{C}$ . ② Pulse Test: Pulse width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$ .  
③  $K_{WM} = 10W$ . ④ Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by  $L_S$ .  
⑤ See Transient Thermal Impedance Curve (Fig. 5).

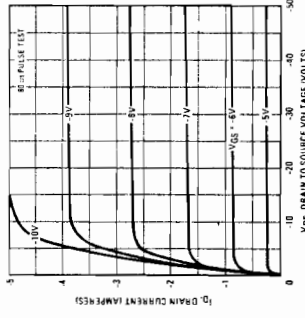


Fig. 1 - Typical Output Characteristics

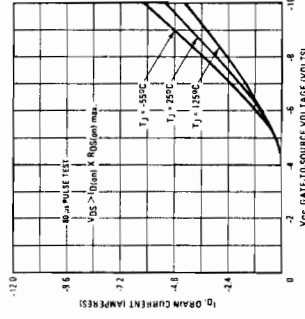


Fig. 2 - Typical Transfer Characteristics

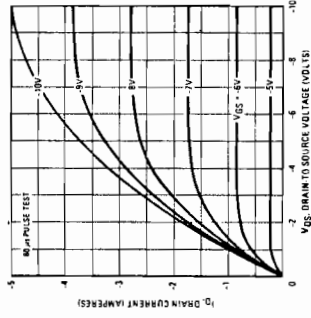


Fig. 3 - Typical Saturation Characteristics

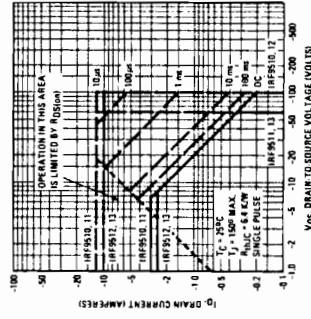


Fig. 4 - Maximum Safe Operating Area

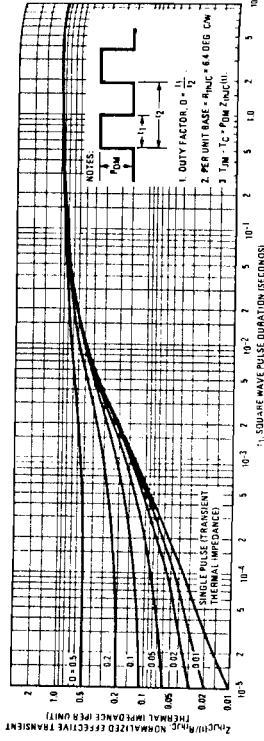


Fig. 5 - Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

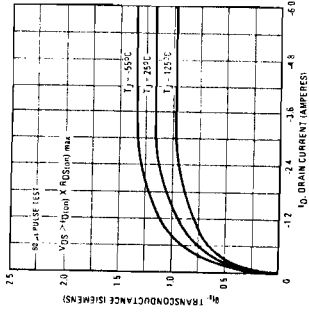


Fig. 6 - Typical Transconductance Vs. Drain Current

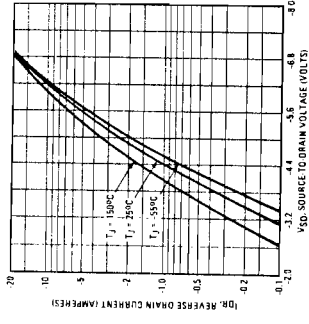


Fig. 7 - Typical Source-Drain Diode Forward Voltage

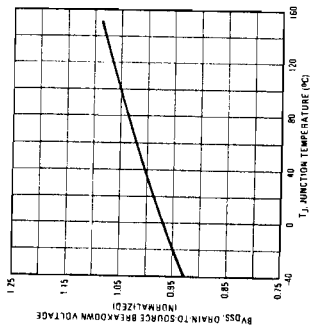


Fig. 8 - Breakdown Voltage Vs. Temperature

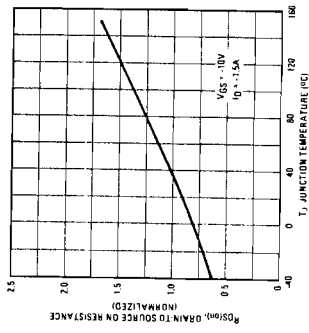


Fig. 9 - Normalized On-Resistance Vs. Temperature

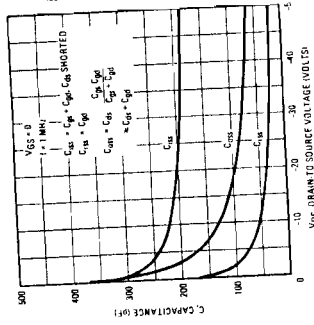


Fig. 10 - Typical Capacitance Vs. Drain-to-Source Voltage

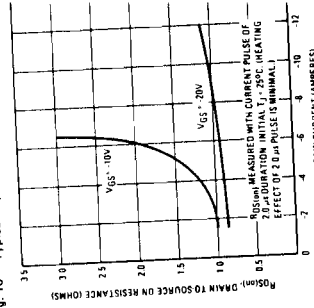


Fig. 11 - Typical Gate Charge Vs. Drain-to-Source Voltage

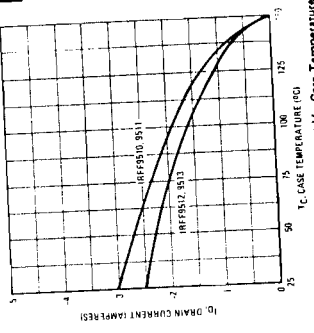


Fig. 12 - Typical On-Resistance Vs. Drain Current

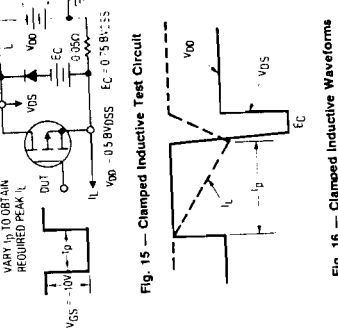


Fig. 13 - Maximum Drain Current Vs. Case Temperature

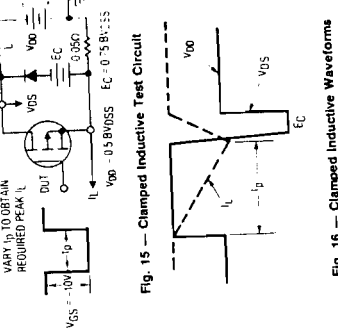


Fig. 14 - Power Vs. Temperature Operating

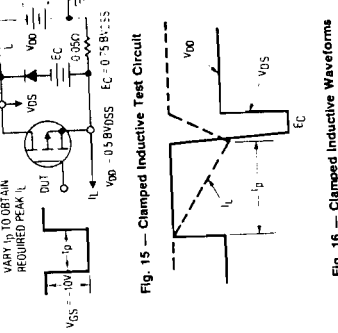


Fig. 15 - Clamped Inductive Test Circuit

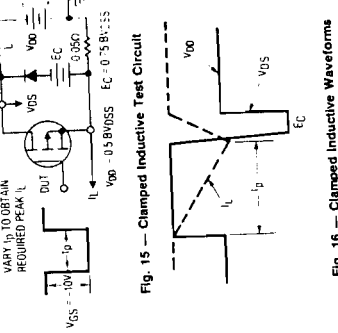
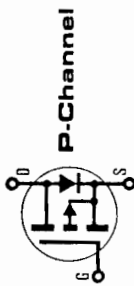


Fig. 16 - Clamped Inductive Waveforms

# INTERNATIONAL RECTIFIER



## HEXFET® TRANSISTORS IRF9520 IRF9521 IRF9522 IRF9523



P-Channel

### -100 Volt, 0.6 Ohm HEXFET TO-220AB Plastic Package

The HEXFET® technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry and unique processing of the HEXFET design achieve very low on-state resistance combined with high transconductance and extreme device ruggedness.

The P-Channel HEXFETs are designed for applications which require the convenience of the more common N-Channel HEXFETs, such as voltage control, very fast switching, ease of paralleling, and excellent temperature stability.

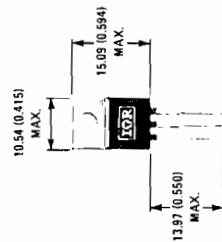
P-Channel HEXFETs are intended for use in power stages where complementary symmetry with N-Channel devices offers circuit simplification. They are also very useful in drive stages because of the circuit versatility offered by their reverse polarity connection. They are well suited for applications requiring switching mode converters, control circuit and pulse amplifiers.

- Features:**
- P-Channel Versatility
  - Compact Plastic Package
  - Fast Switching
  - Low Drive Current
  - Ease of Paralleling
  - Excellent Temperature Stability

### Product Summary

Part Number	VDS	POSS(on)	Id
IRF9520	-100V	0.60Q	-6.0A
IRF9521	-60V	0.60Q	-6.0A
IRF9522	-100V	0.80Q	-5.0A
IRF9523	-60V	0.80Q	-5.0A

### CASE STYLE AND DIMENSIONS



Case Style TO-220AB  
Dimensions in Millimeters and Inches

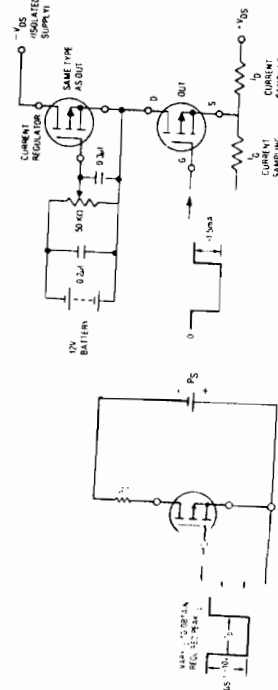


Fig. 17 — Time Test Circuit

Fig. 18 — Gate Charge Test Circuit

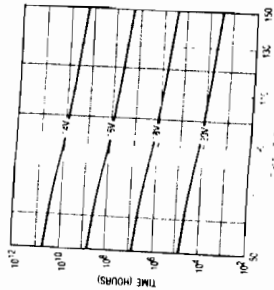


Fig. 19 — Typical  $t_{90}$  : Accumulated 1% Gate Failure

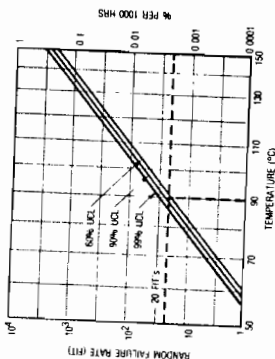


Fig. 20 — Typical High Temperature Reverse Bias (HTRB) Failure Rate

\*The data shown in corner of Fig. 19 is based on a quarterly data for the life of the device. The data is based on a quarterly data for the life of the device.